TOSHIBA SM10LZ47

TOSHIBA BI-DIRECTIONAL TRIODE THYRISTOR SILICON PLANAR TYPE

SM10LZ47

AC POWER CONTROL APPLICATIONS

Repetitive Peak Off-State Voltage: VDRM=800V

R.M.S. On-State Current $: I_{T(RMS)} = 10A$

High Commutation (dv/dt)

: VISOL = 1500V AC Isolation Voltage

MAXIMUM RATINGS

CHARACTERISTIC	SYMBOL	RATING	UNIT	
Repetitive Peak Off-State Voltage	$v_{ m DRM}$	800	V	
R.M.S On-State Current (Full Sine Waveform)	I _{T (RMS)}	10	A	
Peak One Cycle Surge On-State	T	100 (50Hz)	A	
Current (Non-Repetitive)	I_{TSM}	110 (60Hz)		
I ² t Limit Value	${f I}^2{f t}$	50	A^2s	
Critical Rate of Rise of On-State Current (Note)	di / dt	50	A/μs	
Peak Gate Power Dissipation	P_{GM}	5	W	
Average Gate Power Dissipation	PG (AV)	0.5	W	
Peak Gate Voltage	v_{FGM}	10	V	
Peak Gate Current	I_{GM}	2	A	
Junction Temperature	T_{j}	-40~125	°C	
Storage Temperature Range	$\mathrm{T_{stg}}$	-40~125	°C	
Isolation Voltage (AC, t=1min.)	VISOL	1500	V	

ø3.2 ± 0.2 2.54 ± 0.25 Т1 2. T2 3. GATE **JEDEC EIAJ TOSHIBA** 13-10H1A

Unit in mm

Weight: 1.7g

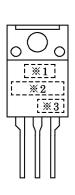
(Note) di/dt test condition $\begin{array}{l} \rm V_{DRM}\!=\!0.5\!\times\!Rated,\;I_{TM}\!\!\leq\!15A,\;t_{gw}\!\!\geq\!10\mu s,\\ t_{gr}\!\!\leq\!250ns,\;i_{gp}\!\!=\!I_{GT}\!\!\times\!2.0 \end{array}$

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ELECTRICAL CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC		SYMBOL	TEST CONDITION		MIN.	TYP.	MAX.	UNIT
Repetitive Peak Off-State Current		$I_{ m DRM}$	V _{DRM} =Rated		_	_	20	μ A
Gate Trigger Voltage	Ι	V_{GT} $V_{\mathrm{D}} = 12 \mathrm{V},$ $R_{\mathrm{L}} = 20 \Omega$		T2(+), GATE(+)	_	_	1.5	
	II		_	= 12(/, OM12(-/)		_	1.5	v
	Ш		T2(-), GATE(-)	_	_	1.5		
Gate Trigger Current	I	1 18 211	$V_D = 12V,$ $R_L = 20\Omega$	T2(+), GATE(+)	_	_	30	mA
	П			T2(+), GATE(-)	_	_	30	
	Ш			T2(-), GATE(-)	_	_	30	
Peak On-State Voltage		V_{TM}	I _{TM} =15A		_	_	1.5	V
Gate Non-Trigger Voltage VGD		v_{GD}	V _D =Rated, Tc=125°C		0.2	_	_	V
Holding Current I _H		$I_{\mathbf{H}}$	$V_D = 12V, I_{TM} = 1A$		_	_	50	mA
Thermal Resistance Rth (j-c) J		Junction to Case, AC		_	_	3.4	°C/W	
Critical Rate of Rise of	ritical Rate of Rise of Off-		$V_{DRM} = 600V, T_j = 125^{\circ}C$			300		V/ va
State Voltage		Exponential Rise		_	300	_	V/μs	
Critical Rate of Rise of	Off-	VDD15-400V T195°C		10		_	V/μs	
State Voltage at Commutation (dv/dt) c		(dv / dt) c	dt) c $V_{DRM} = 400V, T_j = 125^{\circ}C$ (dv/dt) c = -5.5A/ms					
		(dv / dt) c = -5.5A / ms						

MARKING



NUMBER		SYMBOL	MARK		
*1	TOSHIBA PF	RODUCT MARK	7		
*2	TYPE SM10LZ47		M10LZ47		
*3		h (Starting from) (Alphabet A) (Last Decimal Digit) (of the Current Year)	Example 8A: January 1998 8B: February 1998 8L: December 1998		